Search Notes

Application/Control No.	Applicant(s)/Pat Reexamination	Applicant(s)/Patent under Reexamination	
10/787,217	FAULKNER ET AL.		
Examiner	Art Unit		
Apu M. Mofiz	2165		

SEARCHED						
Class	Subclass	Date	Examiner			
カテ	1,10	08/02/66	Bu			
	200,202					
	204					
770	015					
710 711	203,206		J			
	,,	·				

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Inventor Search	08/02/06	ar [		
East - USPAT - USPAPUB - EPO, TPO - IBMTIB - DERWENT				
NPL — ACM — IEEE				
(nothernet) -Google		7		
		<del></del>		